

**July 2009** 

### FDMC6679AZ

# P-Channel PowerTrench® MOSFET -30 V, -20 A, 10 m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 10 \text{ m}\Omega$  at  $V_{GS} = -10 \text{ V}$ ,  $I_D = -11.5 \text{ A}$
- Max  $r_{DS(on)}$  = 18 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -8.5 A
- HBM ESD protection level of 8 kV typical(note 3)
- Extended V<sub>GSS</sub> range (-25 V) for battery applications
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability
- Termination is Lead-free and RoHS Compliant

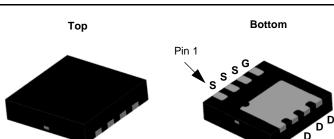
#### **General Description**

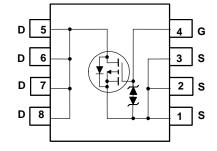
The FDMC6679AZ has been designed to minimize losses in load switch applications. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{DS(on)}$  and ESD protection.

#### **Applications**

- Load Switch in Notebook and Server
- Notebook Battery Pack Power Management







MLP 3.3x3.3

### MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
$V_{DS}$	Drain to Source Voltage			-30	V
$V_{GS}$	Gate to Source Voltage			±25	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		-20	
	-Continuous (Silicon limited)	T <sub>C</sub> = 25 °C		-51	۸
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-11.5	A
	-Pulsed			-32	
D	Power Dissipation	T <sub>C</sub> = 25 °C		41	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.3	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case		3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC6679AZ	FDMC6679AZ	MLP 3.3x3.3	13 "	12 mm	3000 units

### **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °	С	29		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V},$ $V_{GS} = 0 \text{ V},$ $T_{J} = 125 ^{\circ}$	C		-1 -100	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-1.8	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		-7		mV/°C
		$V_{GS} = -10 \text{ V}, I_D = -11.5 \text{ A}$		8.6	10	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -8.5 \text{ A}$		12	18	mΩ
, ,		$V_{GS} = -10 \text{ V}, I_D = -11.5 \text{ A}, T_J = 125 \text{ °C}$		12	15	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -5 V, I <sub>D</sub> = -11.5 A		46		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45 V V 6 V	2985	3970	рF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	570	755	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	500	750	pF
$R_g$	Gate Resistance		4.3		Ω

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time				12	21	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -15 \text{ V}, I_{D} = -17 \text{ V}$	$V_{DD}$ = -15 V, $I_{D}$ = -11.5 A, $V_{GS}$ = -10 V, $R_{GEN}$ = 6 $\Omega$		14	25	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -10 V, R <sub>GEN</sub> :			63	100	ns
t <sub>f</sub>	Fall Time				46	73	ns
$Q_g$	Total Gate Charge	$V_{GS} = 0 \text{ V to -10 V}$			65	91	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to -5 V}$	V <sub>DD</sub> = -15 V,		37	52	nC
$Q_{gs}$	Gate to Source Charge		I <sub>D</sub> = -11.5 A		8.7		nC
$Q_{ad}$	Gate to Drain "Miller" Charge				17		nC

#### **Drain-Source Diode Characteristics**

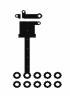
V <sub>SD</sub> Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -11.5 \text{ A}$ (Note 2)		0.83	1.30	\/	
V <sub>SD</sub>	SD Source to Drain Diode Forward voltage	$V_{GS} = 0 \text{ V}, I_S = -1.6 \text{ A}$ (Note 2)		0.71	1.20	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = -11.5 A, di/dt = 100 A/μs		31	49	ns
Q <sub>rr</sub>	Reverse Recovery Charge			16	28	nC

#### NOTES

<sup>1.</sup> R<sub>0,1A</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,1C</sub> is guaranteed by design while R<sub>0,CA</sub> is determined by the user's board design.



a. 53 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b.125 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0 %.
- 3. The diode connected between the gate and source servers only as protection against ESD. No gate overvoltage rating is implied.

### **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

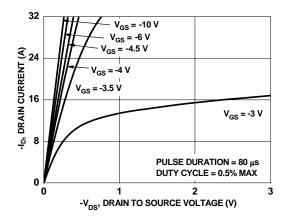


Figure 1. On Region Characteristics

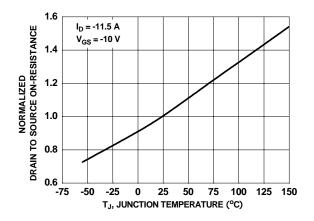


Figure 3. Normalized On Resistance vs Junction Temperature

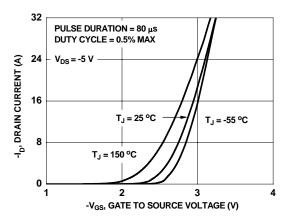


Figure 5. Transfer Characteristics

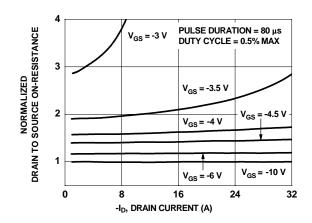


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

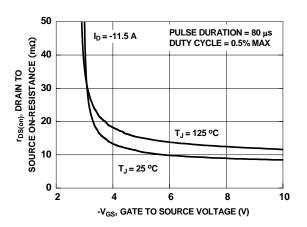


Figure 4. On-Resistance vs Gate to Source Voltage

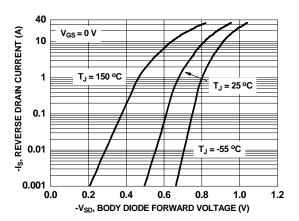


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

### **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

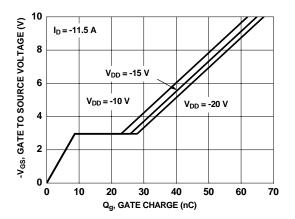


Figure 7. Gate Charge Characteristics

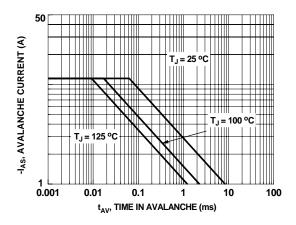


Figure 9. Unclamped Inductive Switching Capability

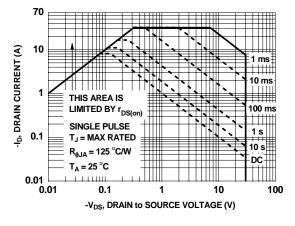


Figure 11. Forward Bias Safe Operating Area

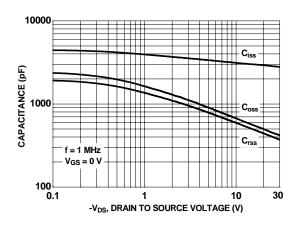


Figure 8. Capacitance vs Drain to Source Voltage

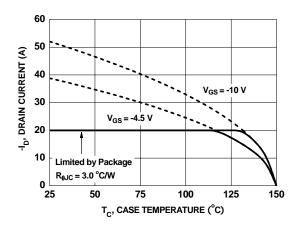


Figure 10. Maximum Continuous Drain Current vs Case Temperature

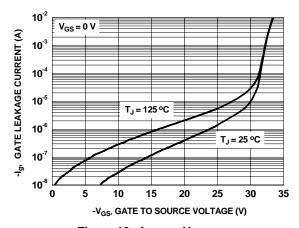


Figure 12. Igss vs Vgss

## Typical Characteristics $T_J = 25$ °C unless otherwise noted

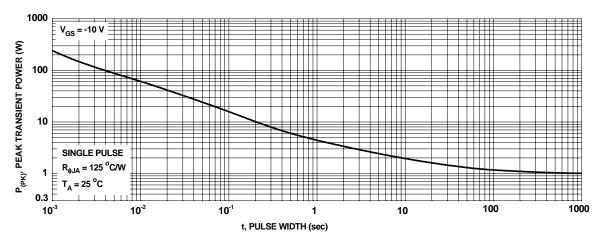


Figure 13. Single Pulse Maximum Power Dissipation

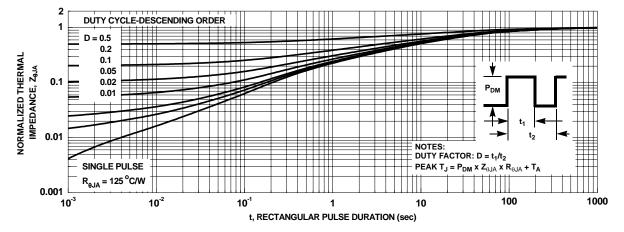
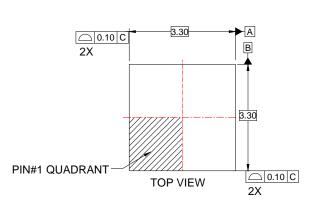
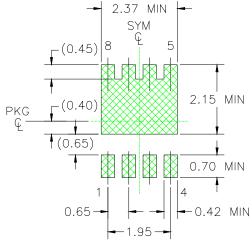


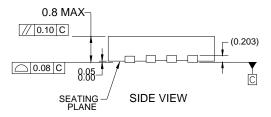
Figure 14. Junction-to-Ambient Transient Thermal Response Curve

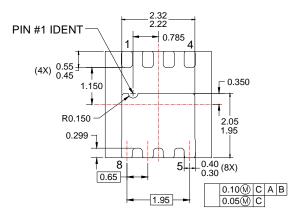
### **Dimensional Outline and Pad Layout**





RECOMMENDED LAND PATTERN





**BOTTOM VIEW** 

#### NOTES:

- A. DOES NOT CONFORM TO JEDEC REGISTRATION MO-229
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. DRAWING FILE NAME: MLP08XREVA
- E. LAND PATTERN RECOMMENDATION IS BASED ON FSC DESIGN ONLY





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Rev. I41